

<b>Notice of References Cited</b>	Application/Control No. 10/047,732	Applicant(s)/Patent Under Reexamination YOSHIHARA ET AL.	
	Examiner Jennifer T Nguyen	Art Unit 2674	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,809,717	10-2004	Asao et al.	345/102
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	NAKAO et al. Pub. No.: US 2004/0041766
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